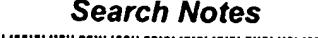


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,851	SHAN ET AL.	
	Examiner	Art Unit	
	Jean W. Désir	2622	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
328	700	2/3/07	
	699,701		
	667,665		